

EAST Search History

L18	1	(capacitance and \$2coupl\$3 and (aggressor or source) and (PCB or (printed near3 board)) and plane and (power or nois\$3 or parasit\$2) and (ratio or comparis\$4 or axcess or differen\$2 or remaind\$3) and effective).clm.	US-PGPUB	OR	ON	2006/07/31 15:16
L19	2	(capacitance and \$2coupl\$3 and (PCB or (printed near3 board)) and plane and (power or nois\$3 or parasit\$2 or aggressor or source) and (ratio or comparis\$4 or axcess or differen\$2 or remaind\$3) and effective).clm.	US-PGPUB	OR	ON	2006/07/31 15:47
L20	2	(capacitance and \$2coupl\$3 and (PCB or (printed near3 board)) and plane and (power or nois\$3 or parasit\$2 or aggressor or source) and (ratio or compar\$4 or axcess or differen\$2 or remaind\$3) and effective).clm.	US-PGPUB	OR	ON	2006/07/31 15:47

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IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

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IEEE STD IEEE Standard

- ☐ **1. Scalable lumped model with multiple physical parameters for embedded passives**
Sheng-Mou Lin; Li-Qun Yang; Hong-Yang Chang;
Electronic Components and Technology, 2005. ECTC '05. Proceedings
31 May-3 June 2005 Page(s):1842 - 1845 Vol. 2
Digital Object Identifier 10.1109/ECTC.2005.1442047
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